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				Application Number	09/957,443
				Filing Date	September 18, 2001
				First Named Inventor	Jason Zweiback
				Art Unit	2872
				Examiner Name	J. Pritchett
Sheet	1	of	1	Attorney Docket Number	64626/P001CP1/10302976

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear ³
		NONE			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² -Number ³ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear ³	T ⁶
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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
HP	CA	Albert, J. et al., "Minimization of Phase Error in Long Fiber Bragg Grating Phase Masksmade Using Electron Beam Lithography," IEEE Photonics Technology Letters, IEEE Inc., New York, US, October 1, 1996, vol. 8, no. 10, pp. 1334-1336		
HP	CB	Tiberio, R.C. et al., "Fabrication of electron beam generated, chirped, phase mask (1070.11-1070.66nm) for fiber Bragg grating dispersion compensator," Journal of Vacuum Science and Technology: Part B, November 1998, vol. 16, no. 6, pp. 3237-3240		
HP	CC	Chakarian, V. et al., "System architecture choices for an advanced mask writer (100-130 nm)," Proceedings of the SPIE, September 1999, vol. 3873, pp. 1-15		
HP	CD	Morgante, C.G., et al., "The ALTA 3700: Extending the Application Space of the ALTA 3500 Laser Recticle Writer," Proceedings of the SPIE, April 2000, vol. 4066, pp. 1-11		
HP	CE	Rishton S.A. et al., "Raster shaped beam pattern generation," Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, November 1999, vol. 17, no. 6, pp. 2927-2931		
HP	CF	Pfeiffer H.C., et al., "EL-4, A New Generation Electron-Beam Lithography System," Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, November 1, 1993, vol. 11, no. 6, pp. 2332-2341		
HP	CG	Hill, K.O., et al., "Fiber Bragg Grating Technology Fundamentals and Overview," Journal of Lightwave Technology, August 1997, vol. 15, no. 8, pp. 1263-1276		
HP	CH	Ericksson, U. et al., "Design of Fiber Gratings For Total Dispersion Compensation," Optics Letters, Optical Society of America, Washington, US, July 15, 1994, vol. 19, no. 14, pp. 1028-1030		
HP	CI	Communication Relating to the Results of the Partial International Search, PCT/US01/29178, mailed August 20, 2003		

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